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(71) Applicant (*for all designated States except US*): KONINKLIJKE PHILIPS ELECTRONICS N.V. [NL/NL]; Groenewoudseweg 1, NL-5621 BA Eindhoven (NL).

(72) Inventor; and

(75) Inventor/Applicant (*for US only*): HEESSELS, Adrianus, C., L. [NL/NL]; c/o Prof. Holstlaan 6, NL-5656 AA Eindhoven (NL).

(74) Agent: DUIJVESTIJN, Adrianus, J.; Internationaal Octrooibureau B.V., Prof. Holstlaan 6, NL-5656 AA Eindhoven (NL).

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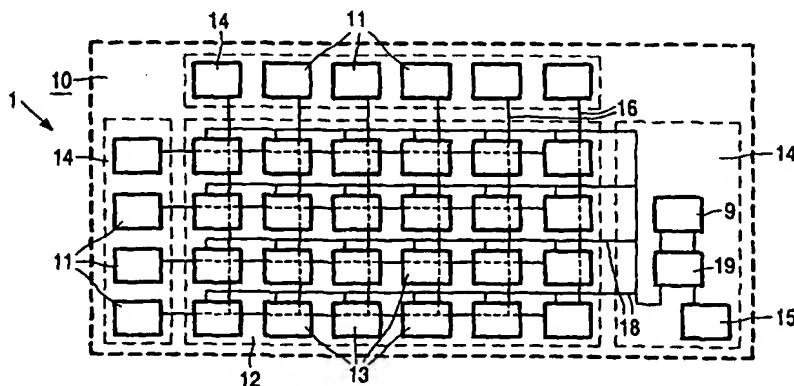
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(54) Title: INTEGRATED CIRCUIT AND METHOD OF MANUFACTURING SAME



(57) Abstract: The integrated circuit (1) according to the invention comprises a set of cells (10), each of the cells (11, 13, 15, 19) comprises an electrical device (20) with a device parameter whose parameter value is a function of random parametric variations. The set of cells (10) comprises a first subset (12) of identification cells (13) with first random parametric variations, and a second subset (14) of cells (11, 15, 19), which are able to generate an identification code by measuring the random differences between the parameter values of the identification cells (13). According to the invention the cells (11, 15, 19) of the second

subset (14) have second random parametric variations, which are smaller than the first random parametric variations, thereby making the generation of the identification code relatively easy.

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